Application/Control No. 10/084,182 Examiner Yvette C. Thornton Applicant(s)/Patent Under Reexamination NAKANISHI ET AL. Page 1 of 1

Notice of References Cited

U.S. PATENT DOCUMENTS

		,		U.S. PATENT DOCUMENTS	
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	. Name	Classification
	Α	US-2002/0034704 A1	03-2002	Oomori et al.	430/270.1
	В	US-6,492,086 B1	12-2002	Barclay et al.	430/270.1
	. c	US-5,952,151 A	09-1999	Sondergeld, Manfred	430/270.1
	D.	US-5,846,690 A	12-1998	Padmanaban et al.	430/284.1
	Ε	US-			·
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	,				
	0					
	Р					
	Q.					
	R					
	s			,		
	Т					

NON-PATENT DOCUMENTS

	MON-FAILNI DOCUMENTO								
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)							
	υ	MACHINE TRANSLATION FROM JPO WEBSITE JP 2001-027809 ITANI ET AL. "CHEMICAL AMPLIFICATION SERIES POSITIVE TYPE RESIST".							
	٧								
	w								
	x								

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.